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APPLICANT : YAMAHA CORP;

INVENTOR : IIDA SHUNICHI;

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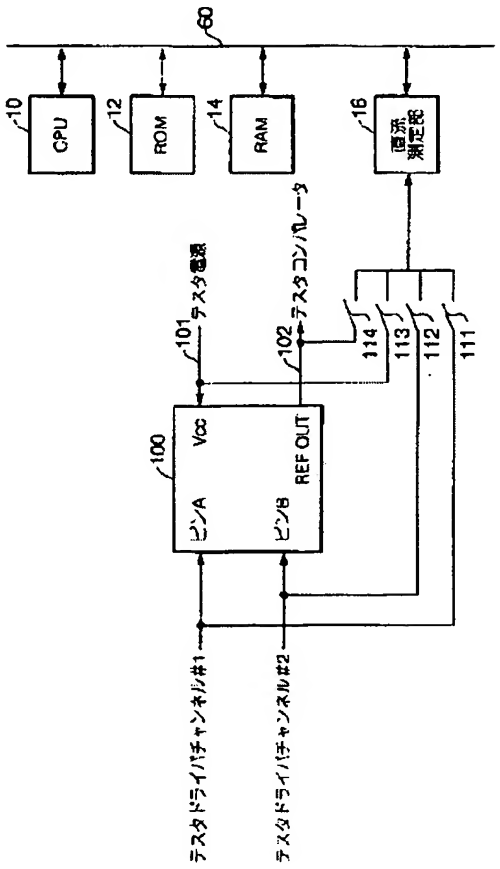
TITLE : SEMICONDUCTOR INTEGRATED CIRCUIT TESTING DEVICE, CALIBRATION METHOD FOR IT, AND RECORDING MEDIUM



ABSTRACT : PROBLEM TO BE SOLVED: To suppress a relative error of a voltage set value fed to each pin of a measured device within the resolution range of a measurement system.

SOLUTION: The semiconductor integrated circuit testing device is provided with a common-use direct current measurement part 16 measuring an actual voltage value, which is fed from a specific related circuit in the semiconductor integrated circuit testing device connected to respective pins of a measured device 100 to the respective pin, for every pin during inspection of the measured device, a ROM 12 storing a voltage preset value fed to each pin of the measured device during the inspection time, and a CPU 10 finding an error between a voltage measurement value measured by means of the direct current measurement part 16 and fed to each pin and the preset value for every pin, performing feedback so that a voltage value having the opposite polarity to the error polarity and serving as a correction value is impressed to a pin having an error above an allowance value in the measured device and setting a supply voltage so as to lower the error below the allowance value.